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Descrizione fisica	1 online resource (XV, 693 p. 318 illus., 227 illus. in color.)
Collana	Image Processing, Computer Vision, Pattern Recognition, and Graphics, , 3004-9954 ; ; 12306
Disciplina	006.4
Soggetti	Computer vision Social sciences - Data processing Education - Data processing Machine learning Computer networks Computer systems Computer Vision Computer Application in Social and Behavioral Sciences Computers and Education Machine Learning Computer Communication Networks Computer System Implementation
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Nota di contenuto	Computing methodologies -- Machine learning -- Machine learning approaches -- Neural networks -- Biometrics Tracking -- Image segmentation -- Video segmentation -- Object detection -- Object recognition -- Computer vision -- Artificial intelligence -- Machine learning algorithms.
Sommario/riassunto	The three-volume set LNCS 12305, 12306, and 12307 constitutes the refereed proceedings of the Third Chinese Conference on Pattern Recognition and Computer Vision, PRCV 2020, held virtually in Nanjing, China, in October 2020. The 158 full papers presented were carefully reviewed and selected from 402 submissions. The papers have been organized in the following topical sections: Part I: Computer Vision and Application, Part II: Pattern Recognition and Application, Part III: Machine Learning.